

Notice of References Cited	Application/Control No. 10/560,856	Applicant(s)/Patent Under Reexamination MUROSAWA ET AL.	
	Examiner Tai Van Nguyen	Art Unit 3729	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,245,171	06-2001	Natarajan et al.	156/89.11
	B	US-4,556,757	12-1985	Oberbach, Josef	174/384
	C	US-4,297,522	10-1981	Jesse et al.	174/27
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	2003-095740	10-2004	Japan	Suzuki Kazutaka et al.	H01G 4/30
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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